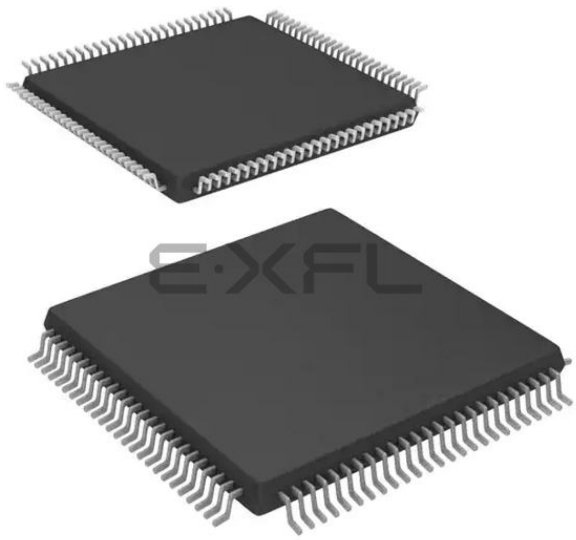


Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	42
Number of Logic Elements/Cells	336
Total RAM Bits	-
Number of I/O	78
Number of Gates	4000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epf8452atc100-2

FLEX 8000 devices contain an optimized microprocessor interface that permits the microprocessor to configure FLEX 8000 devices serially, in parallel, synchronously, or asynchronously. The interface also enables the microprocessor to treat a FLEX 8000 device as memory and configure the device by writing to a virtual memory location, making it very easy for the designer to create configuration software.

The FLEX 8000 family is supported by Altera's MAX+PLUS II development system, a single, integrated package that offers schematic, text—including the Altera Hardware Description Language (AHDL), VHDL, and Verilog HDL—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The MAX+PLUS II software provides EDIF 2 0 0 and 3 0 0, library of parameterized modules (LPM), VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX workstation-based EDA tools. The MAX+PLUS II software runs on Windows-based PCs and Sun SPARCstation, HP 9000 Series 700/800, and IBM RISC System/6000 workstations.

The MAX+PLUS II software interfaces easily with common gate array EDA tools for synthesis and simulation. For example, the MAX+PLUS II software can generate Verilog HDL files for simulation with tools such as Cadence Verilog-XL. Additionally, the MAX+PLUS II software contains EDA libraries that use device-specific features such as carry chains, which are used for fast counter and arithmetic functions. For instance, the Synopsys Design Compiler library supplied with the MAX+PLUS II development system includes DesignWare functions that are optimized for the FLEX 8000 architecture.

For more information on the MAX+PLUS II software, go to the *MAX+PLUS II Programmable Logic Development System & Software Data Sheet*.

Functional Description

The FLEX 8000 architecture incorporates a large matrix of compact building blocks called logic elements (LEs). Each LE contains a 4-input LUT that provides combinatorial logic capability and a programmable register that offers sequential logic capability. The fine-grained structure of the LE provides highly efficient logic implementation.

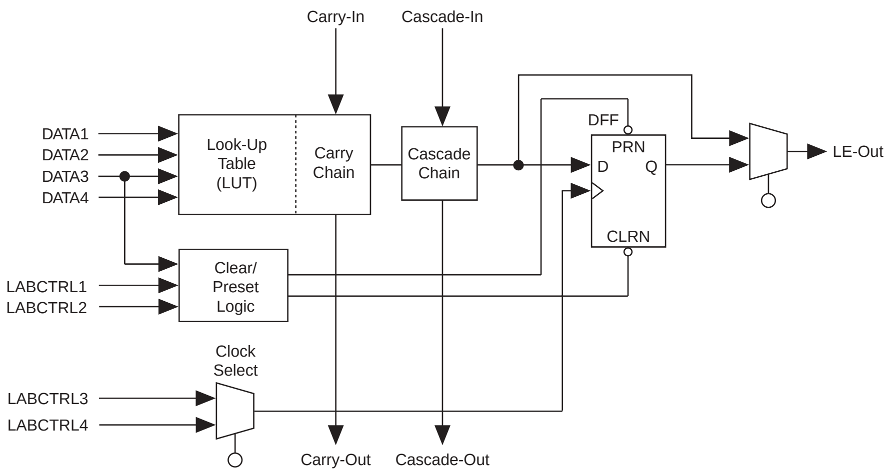
Eight LEs are grouped together to form a logic array block (LAB). Each FLEX 8000 LAB is an independent structure with common inputs, interconnections, and control signals. The LAB architecture provides a coarse-grained structure for high device performance and easy routing.

Each LAB provides four control signals that can be used in all eight LEs. Two of these signals can be used as clocks, and the other two for clear/preset control. The LAB control signals can be driven directly from a dedicated input pin, an I/O pin, or any internal signal via the LAB local interconnect. The dedicated inputs are typically used for global clock, clear, or preset signals because they provide synchronous control with very low skew across the device. FLEX 8000 devices support up to four individual global clock, clear, or preset control signals. If logic is required on a control signal, it can be generated in one or more LEs in any LAB and driven into the local interconnect of the target LAB.

Logic Element

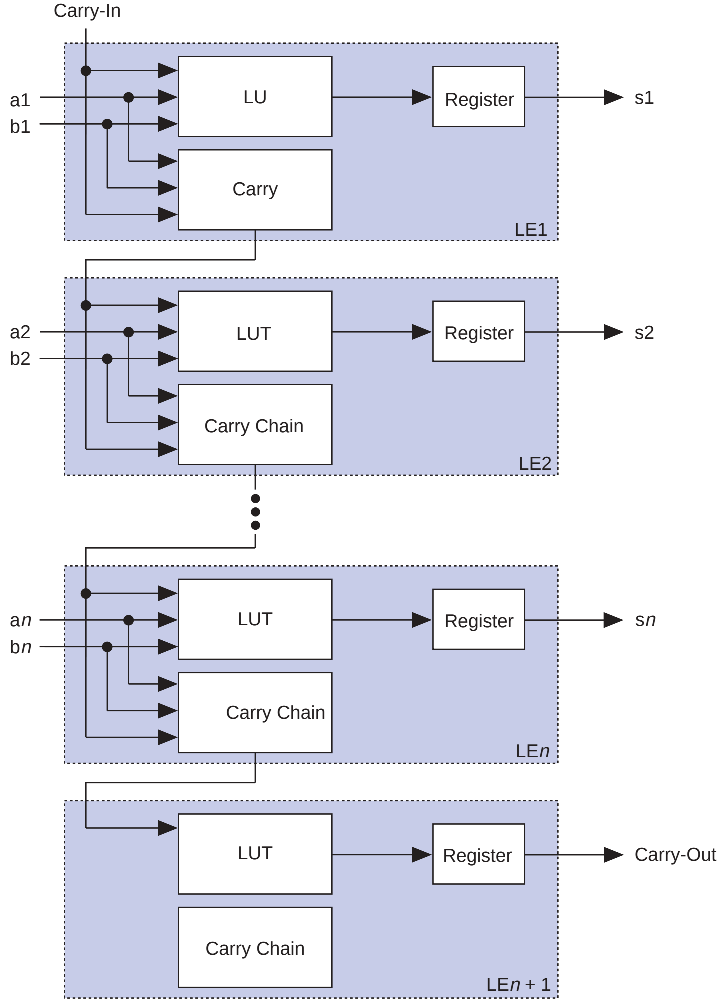
The logic element (LE) is the smallest unit of logic in the FLEX 8000 architecture, with a compact size that provides efficient logic utilization. Each LE contains a 4-input LUT, a programmable flipflop, a carry chain, and cascade chain. Figure 3 shows a block diagram of an LE.

Figure 3. FLEX 8000 LE



The LUT is a function generator that can quickly compute any function of four variables. The programmable flipflop in the LE can be configured for D, T, JK, or SR operation. The clock, clear, and preset control signals on the flipflop can be driven by dedicated input pins, general-purpose I/O pins, or any internal logic. For purely combinatorial functions, the flipflop is bypassed and the output of the LUT goes directly to the output of the LE.

Figure 4. FLEX 8000 Carry Chain Operation



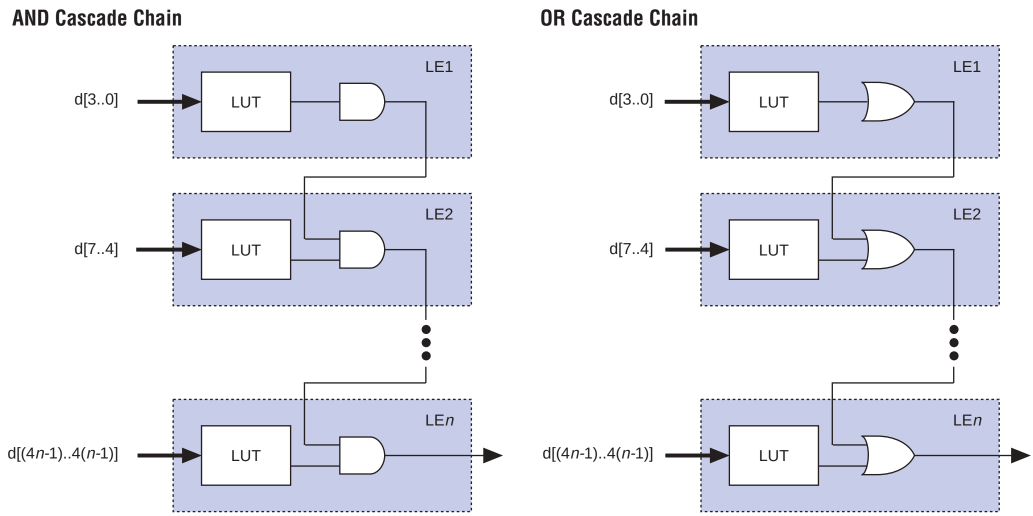
Cascade Chain

With the cascade chain, the FLEX 8000 architecture can implement functions that have a very wide fan-in. Adjacent LUTs can be used to compute portions of the function in parallel; the cascade chain serially connects the intermediate values. The cascade chain can use a logical AND or logical OR (via De Morgan's inversion) to connect the outputs of adjacent LEs. Each additional LE provides four more inputs to the effective width of a function, with a delay as low as 0.6 ns per LE.

The MAX+PLUS II Compiler can create cascade chains automatically during design processing; designers can also insert cascade chain logic manually during design entry. Cascade chains longer than eight LEs are automatically implemented by linking LABs together. The last LE of an LAB cascades to the first LE of the next LAB.

Figure 5 shows how the cascade function can connect adjacent LEs to form functions with a wide fan-in. These examples show functions of 4*n* variables implemented with *n* LEs. For a device with an A-2 speed grade, the LE delay is 2.4 ns; the cascade chain delay is 0.6 ns. With the cascade chain, 4.2 ns is needed to decode a 16-bit address.

Figure 5. FLEX 8000 Cascade Chain Operation



LE Operating Modes

The FLEX 8000 LE can operate in one of four modes, each of which uses LE resources differently. See Figure 6. In each mode, seven of the ten available inputs to the LE—the four data inputs from the LAB local interconnect, the feedback from the programmable register, and the carry-in and cascade-in from the previous LE—are directed to different destinations to implement the desired logic function. The three remaining inputs to the LE provide clock, clear, and preset control for the register. The MAX+PLUS II software automatically chooses the appropriate mode for each application. Design performance can also be enhanced by designing for the operating mode that supports the desired application.

Figure 7. FLEX 8000 LE Asynchronous Clear & Preset Modes

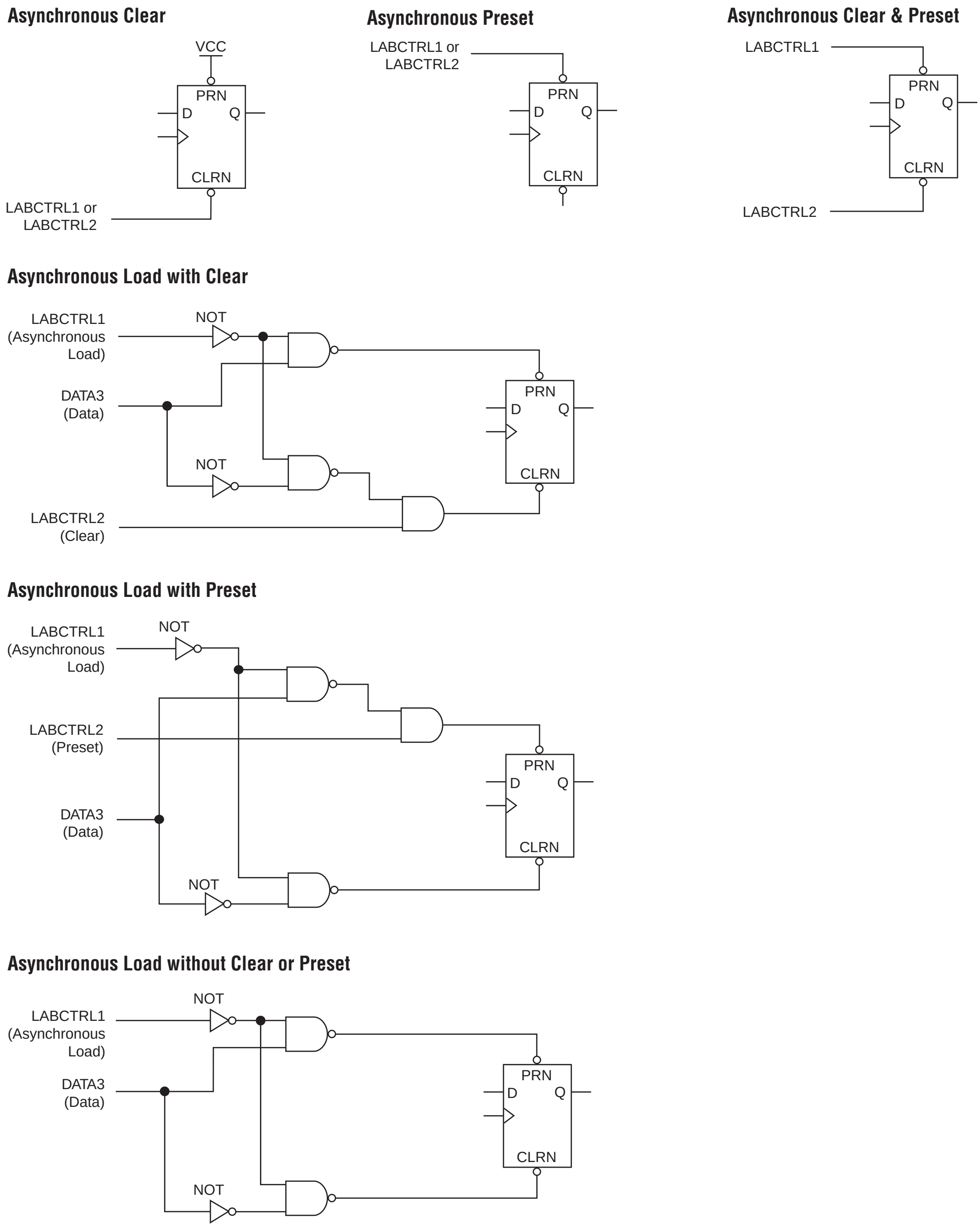
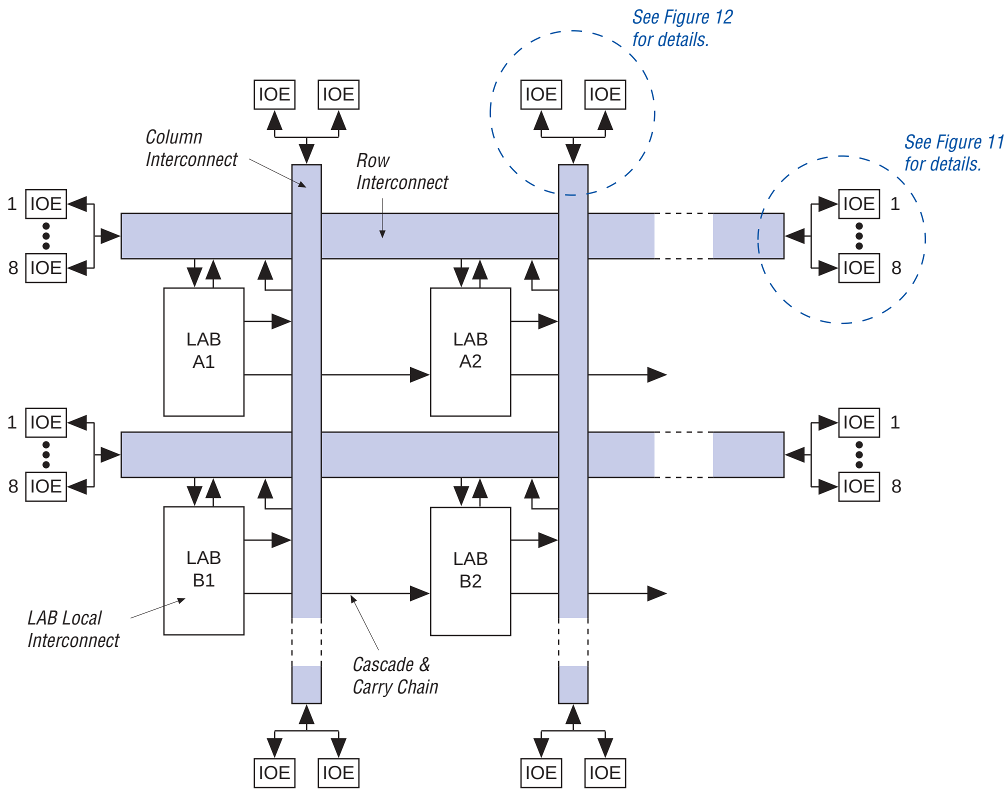


Figure 9. FLEX 8000 Device Interconnect Resources

Each LAB is named according to its physical row (A, B, C, etc.) and column (1, 2, 3, etc.) position within the device.

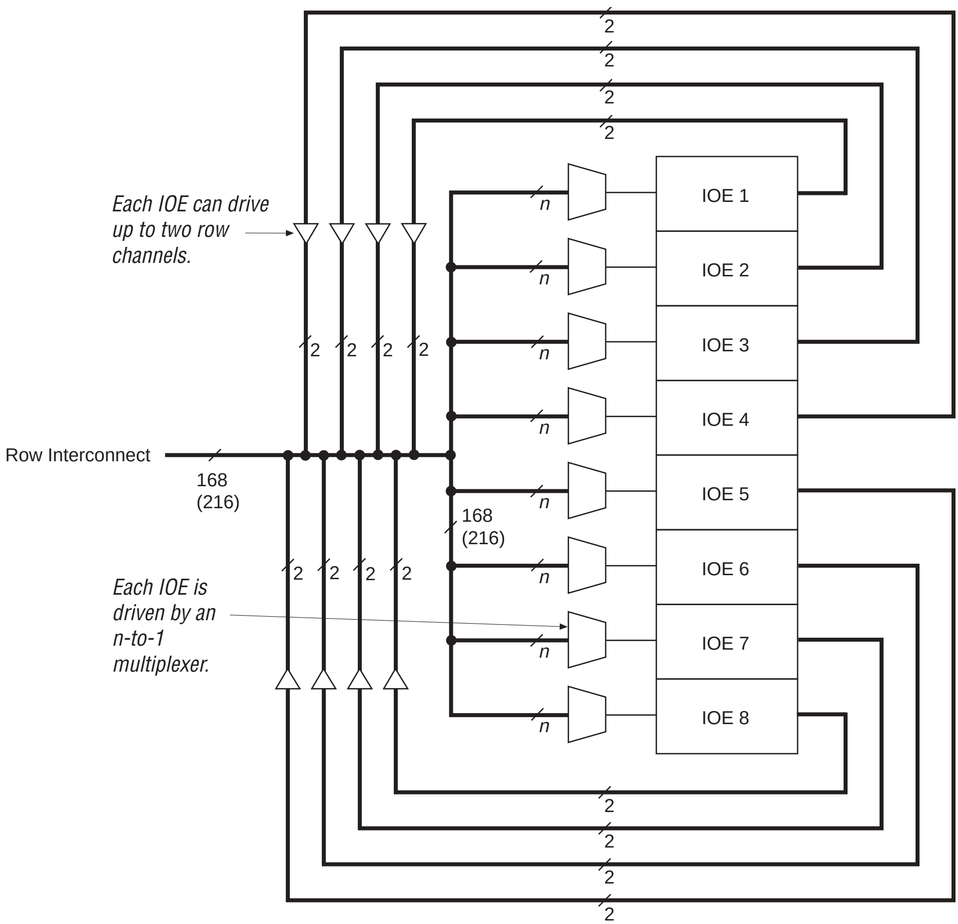


I/O Element

An IOE contains a bidirectional I/O buffer and a register that can be used either as an input register for external data that requires a fast setup time, or as an output register for data that requires fast clock-to-output performance. IOEs can be used as input, output, or bidirectional pins. The MAX+PLUS II Compiler uses the programmable inversion option to automatically invert signals from the row and column interconnect where appropriate. Figure 10 shows the IOE block diagram.

Figure 11. FLEX 8000 Row-to-IOE Connections

Numbers in parentheses are for EPF81500A devices. See Note (1).



Note:

(1) n = 13 for EPF8282A and EPF8282AV devices.
n = 21 for EPF8452A, EPF8636A, EPF8820A, and EPF81188A devices.
n = 27 for EPF81500A devices.

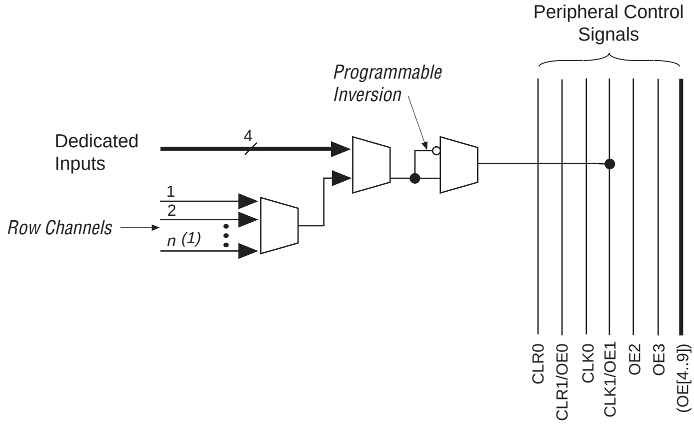
Column-to-IOE Connections

Two IOEs are located at the top and bottom of the column channels (see Figure 12). When an IOE is used as an input, it can drive up to two separate column channels. The output signal to an IOE can choose from 8 of the 16 column channels through an 8-to-1 multiplexer.

The signals for the peripheral bus can be generated by any of the four dedicated inputs or signals on the row interconnect channels, as shown in Figure 13. The number of row channels in a row that can drive the peripheral bus correlates to the number of columns in the FLEX 8000 device. EPF8282A and EPF8282AV devices use 13 channels; EPF8452A, EPF8636A, EPF8820A, and EPF81188A devices use 21 channels; and EPF81500A devices use 27 channels. The first LE in each LAB is the source of the row channel signal. The six peripheral control signals (12 in EPF81500A devices) can be accessed by each IOE.

Figure 13. FLEX 8000 Peripheral Bus

Numbers in parentheses are for EPF81500A devices.



Note:

(1) n = 13 for EPF8282A and EPF8282AV devices.
n = 21 for EPF8452A, EPF8636A, EPF8820A, and EPF81188A devices.
n = 27 for EPF81500A devices.

The instruction register length for FLEX 8000 devices is three bits. Table 7 shows the boundary-scan register length for FLEX 8000 devices.

Table 7. FLEX 8000 Boundary-Scan Register Length

Device	Boundary-Scan Register Length
EPF8282A, EPF8282AV	273
EPF8636A	417
EPF8820A	465
EPF81500A	645

FLEX 8000 devices that support JTAG include weak pull-ups on the JTAG pins. Figure 14 shows the timing requirements for the JTAG signals.

Figure 14. EPF8282A, EPF8282AV, EPF8636A, EPF8820A & EPF81500A JTAG Waveforms

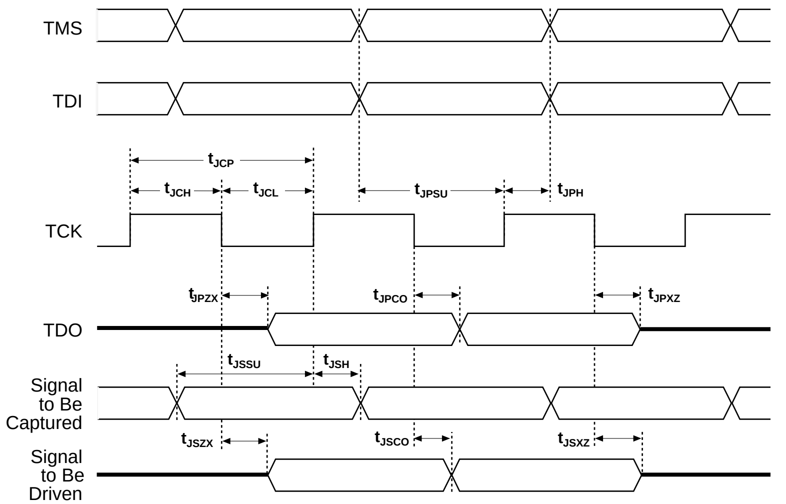
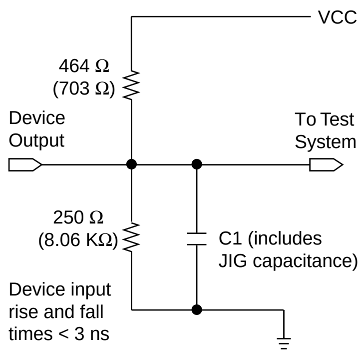


Table 8 shows the timing parameters and values for EPF8282A, EPF8282AV, EPF8636A, EPF8820A, and EPF81500A devices.

Figure 15. FLEX 8000 AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast-ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in parentheses are for 3.3-V devices or outputs. Numbers without parentheses are for 5.0-V devices or outputs.



Operating Conditions

Tables 9 through 12 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 5.0-V FLEX 8000 devices.

Table 9. FLEX 8000 5.0-V Device Absolute Maximum Ratings *Note (1)*

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	Supply voltage	With respect to ground *(2)*	–2.0	7.0	V
V_I	DC input voltage		–2.0	7.0	V
I_{OUT}	DC output current, per pin		–25	25	mA
T_{STG}	Storage temperature	No bias	–65	150	° C
T_{AMB}	Ambient temperature	Under bias	–65	135	° C
T_J	Junction temperature	Ceramic packages, under bias		150	° C
		PQFP and RQFP, under bias		135	° C

Table 10. FLEX 8000 5.0-V Device Recommended Operating Conditions					
Symbol	**Parameter**	**Conditions**	**Min**	**Max**	**Unit**
V_{CCINT}	Supply voltage for internal logic and input buffers	*(3)*, *(4)*	4.75 (4.50)	5.25 (5.50)	V
V_{CCIO}	Supply voltage for output buffers, 5.0-V operation	*(3)*, *(4)*	4.75 (4.50)	5.25 (5.50)	V
	Supply voltage for output buffers, 3.3-V operation	*(3)*, *(4)*	3.00 (3.00)	3.60 (3.60)	V
V_I	Input voltage		–0.5	V_{CCINT} + 0.5	V
V_O	Output voltage		0	V_{CCIO}	V
T_A	Operating temperature	For commercial use	0	70	° C
		For industrial use	–40	85	° C
t_R	Input rise time			40	ns
t_F	Input fall time			40	ns

Table 11. FLEX 8000 5.0-V Device DC Operating Conditions *Notes (5), (6)*						
Symbol	**Parameter**	**Conditions**	**Min**	**Typ**	**Max**	**Unit**
V_{IH}	High-level input voltage		2.0		V_{CCINT} + 0.5	V
V_{IL}	Low-level input voltage		–0.5		0.8	V
V_{OH}	5.0-V high-level TTL output voltage	I_{OH} = –4 mA DC *(7)* V_{CCIO} = 4.75 V	2.4			V
	3.3-V high-level TTL output voltage	I_{OH} = –4 mA DC *(7)* V_{CCIO} = 3.00 V	2.4			V
	3.3-V high-level CMOS output voltage	I_{OH} = –0.1 mA DC *(7)* V_{CCIO} = 3.00 V	V_{CCIO} – 0.2			V
V_{OL}	5.0-V low-level TTL output voltage	I_{OL} = 12 mA DC *(7)* V_{CCIO} = 4.75 V			0.45	V
	3.3-V low-level TTL output voltage	I_{OL} = 12 mA DC *(7)* V_{CCIO} = 3.00 V			0.45	V
	3.3-V low-level CMOS output voltage	I_{OL} = 0.1 mA DC *(7)* V_{CCIO} = 3.00 V			0.2	V
I_I	Input leakage current	V_I = V_{CC} or ground	–10		10	µA
I_{OZ}	Tri-state output off-state current	V_O = V_{CC} or ground	–40		40	µA
I_{CC0}	V_{CC} supply current (standby)	V_I = ground, no load		0.5	10	mA

Table 12. FLEX 8000 5.0-V Device Capacitance *Note (8)*

Symbol	Parameter	Conditions	Min	Max	Unit
C_{IN}	Input capacitance	V_{IN} = 0 V, f = 1.0 MHz		10	pF
C_{OUT}	Output capacitance	V_{OUT} = 0 V, f = 1.0 MHz		10	pF

Notes to tables:

(1) See the *Operating Requirements for Altera Devices Data Sheet*.
(2) Minimum DC input is –0.5 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 7.0 V for input currents less than 100 mA and periods shorter than 20 ns.
(3) The maximum V_{CC} rise time is 100 ms.
(4) Numbers in parentheses are for industrial-temperature-range devices.
(5) Typical values are for T_A = 25° C and V_{CC} = 5.0 V.
(6) These values are specified in Table 10 on page 28.
(7) The I_{OH} parameter refers to high-level TTL or CMOS output current; the I_{OL} parameter refers to low-level TTL or CMOS output current.
(8) Capacitance is sample-tested only.

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 3.3-V FLEX 8000 devices.

Table 13. FLEX 8000 3.3-V Device Absolute Maximum Ratings *Note (1)*

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	Supply voltage	With respect to ground *(2)*	–2.0	5.3	V
V_I	DC input voltage		–2.0	5.3	V
I_{OUT}	DC output current, per pin		–25	25	mA
T_{STG}	Storage temperature	No bias	–65	150	° C
T_{AMB}	Ambient temperature	Under bias	–65	135	° C
T_J	Junction temperature	Plastic packages, under bias		135	° C

Table 14. FLEX 8000 3.3-V Device Recommended Operating Conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	Supply voltage	*(3)*	3.0	3.6	V
V_I	Input voltage		–0.3	V_{CC} + 0.3	V
V_O	Output voltage		0	V_{CC}	V
T_A	Operating temperature	For commercial use	0	70	° C
t_R	Input rise time			40	ns
t_F	Input fall time			40	ns

Table 15. FLEX 8000 3.3-V Device DC Operating Conditions *Note (4)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IH}	High-level input voltage		2.0		V_{CC} + 0.3	V
V_{IL}	Low-level input voltage		–0.3		0.8	V
V_{OH}	High-level output voltage	I_{OH} = –0.1 mA DC *(5)*	V_{CC} – 0.2			V
V_{OL}	Low-level output voltage	I_{OL} = 4 mA DC *(5)*			0.45	V
I_I	Input leakage current	V_I = V_{CC} or ground	–10		10	µA
I_{OZ}	Tri-state output off-state current	V_O = V_{CC} or ground	–40		40	µA
I_{CC0}	V_{CC} supply current (standby)	V_I = ground, no load *(6)*		0.3	10	mA

Table 16. FLEX 8000 3.3-V Device Capacitance *Note (7)*

Symbol	Parameter	Conditions	Min	Max	Unit
C_{IN}	Input capacitance	V_{IN} = 0 V, f = 1.0 MHz		10	pF
C_{OUT}	Output capacitance	V_{OUT} = 0 V, f = 1.0 MHz		10	pF

Notes to tables:

(1) See the *Operating Requirements for Altera Devices Data Sheet*.
(2) Minimum DC input voltage is –0.3 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 5.3 V for input currents less than 100 mA and periods shorter than 20 ns.
(3) The maximum V_{CC} rise time is 100 ms. V_{CC} must rise monotonically.
(4) These values are specified in Table 14 on page 29.
(5) The I_{OH} parameter refers to high-level TTL output current; the I_{OL} parameter refers to low-level TTL output current.
(6) Typical values are for T_A = 25° C and V_{CC} = 3.3 V.
(7) Capacitance is sample-tested only.

Figure 16 shows the typical output drive characteristics of 5.0-V FLEX 8000 devices. The output driver is compliant with ***PCI Local Bus Specification, Revision 2.2***.

Figure 19. FLEX 8000 Timing Model

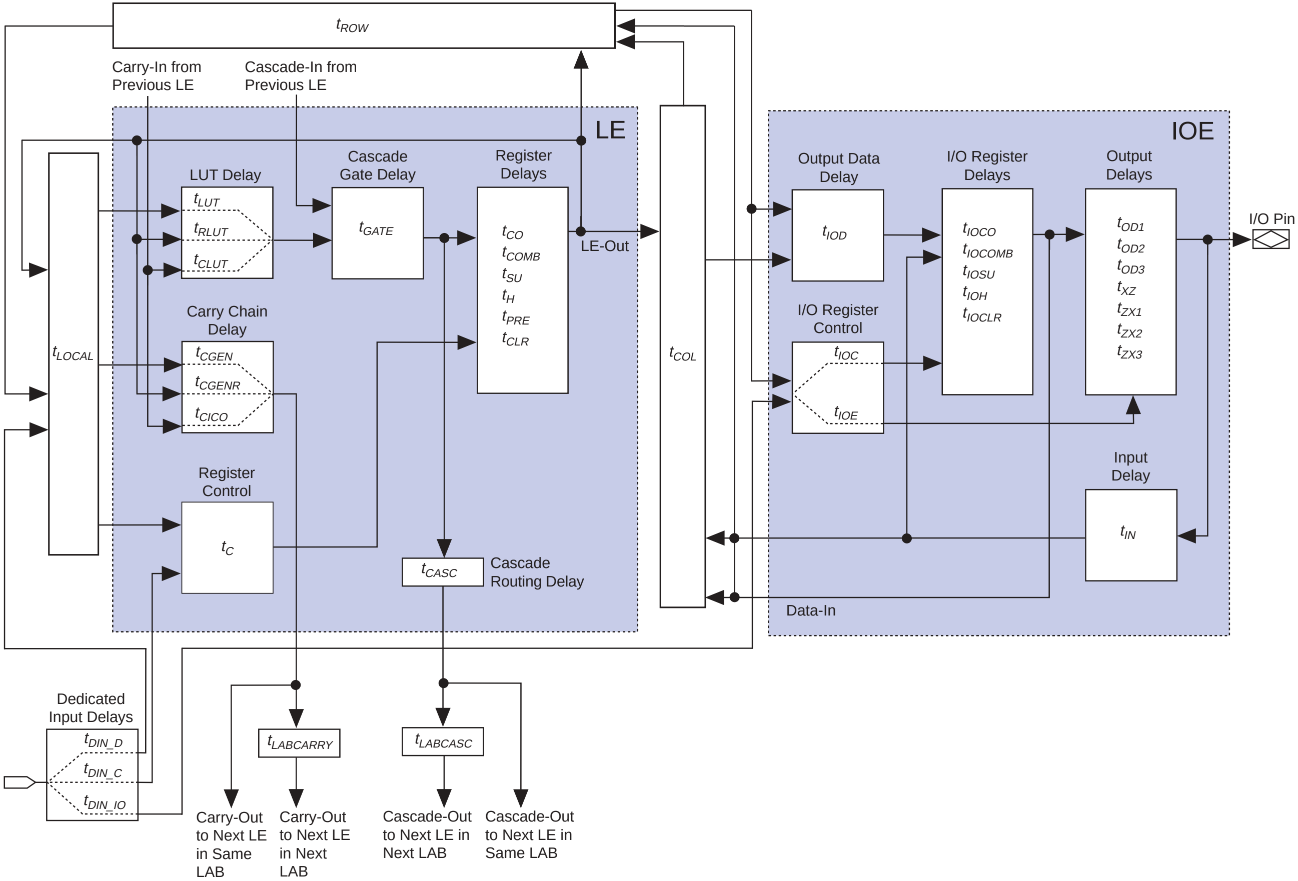


Table 23. EPF8282A Interconnect Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.3		0.4	ns
$t_{LABCARRY}$		0.3		0.3		0.4	ns
t_{LOCAL}		0.5		0.6		0.8	ns
t_{ROW}		4.2		4.2		4.2	ns
t_{COL}		2.5		2.5		2.5	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.2		7.2		7.2	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 30. EPF8452A I/O Element Timing Parameters							
Symbol	**Speed Grade**						**Unit**
	A-2		**A-3**		**A-4**		
	Min	**Max**	**Min**	**Max**	**Min**	**Max**	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		–		–		–	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		–		–		–	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 31. EPF8452A Interconnect Timing Parameters							
Symbol	**Speed Grade**						**Unit**
	A-2		**A-3**		**A-4**		
	Min	**Max**	**Min**	**Max**	**Min**	**Max**	
$t_{LABCASC}$		0.3		0.4		0.4	ns
$t_{LABCARRY}$		0.3		0.4		0.4	ns
t_{LOCAL}		0.5		0.5		0.7	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 32. EPF8452A LE Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		2.0		2.3		3.0	ns
t_{CLUT}		0.0		0.2		0.1	ns
t_{RLUT}		0.9		1.6		1.6	ns
t_{GATE}		0.0		0.0		0.0	ns
t_{CASC}		0.6		0.7		0.9	ns
t_{CICO}		0.4		0.5		0.6	ns
t_{CGEN}		0.4		0.9		0.8	ns
t_{CGENR}		0.9		1.4		1.5	ns
t_{C}		1.6		1.8		2.4	ns
t_{CH}	4.0		4.0		4.0		ns
t_{CL}	4.0		4.0		4.0		ns
t_{CO}		0.4		0.5		0.6	ns
t_{COMB}		0.4		0.5		0.6	ns
t_{SU}	0.8		1.0		1.1		ns
t_{H}	0.9		1.1		1.4		ns
t_{PRE}		0.6		0.7		0.8	ns
t_{CLR}		0.6		0.7		0.8	ns

Table 33. EPF8452A External Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{DRR}		16.0		20.0		25.0	ns
t_{ODH}	1.0		1.0		1.0		ns

Table 52. FLEX 8000 84-, 100-, 144- & 160-Pin Package Pin-Outs (Part 2 of 3)

Pin Name	84-Pin PLCC EPF8282A	84-Pin PLCC EPF8452A EPF8636A	100-Pin TQFP EPF8282A EPF8282AV	100-Pin TQFP EPF8452A	144-Pin TQFP EPF8820A	160-Pin PGA EPF8452A	160-Pin PQFP EPF8820A *(1)*
ADD0	78	76	78	77	106	N3	6
DATA7	3	2	90	89	131	P8	140
DATA6	4	4	91	91	132	P10	139
DATA5	6	6	92	95	133	R12	138
DATA4	7	7	95	96	134	R13	136
DATA3	8	8	97	97	135	P13	135
DATA2	9	9	99	98	137	R14	133
DATA1	13	13	4	4	138	N15	132
DATA0	14	14	5	5	140	K13	129
SDOUT *(3)*	79	78	79	79	23	P4	97
TDI *(4)*	55	45 *(5)*	54	–	96	–	17
TDO *(4)*	27	27 *(5)*	18	–	18	–	102
TCK *(4)*, *(6)*	72	44 *(5)*	72	–	88	–	27
TMS *(4)*	20	43 *(5)*	11	–	86	–	29
TRST *(7)*	52	52 *(8)*	50	–	71	–	45
Dedicated Inputs *(10)*	12, 31, 54, 73	12, 31, 54, 73	3, 23, 53, 73	3, 24, 53, 74	9, 26, 82, 99	C3, D14, N2, R15	14, 33, 94, 113
VCCINT	17, 38, 59, 80	17, 38, 59, 80	6, 20, 37, 56, 70, 87	9, 32, 49, 59, 82	8, 28, 70, 90, 111	B2, C4, D3, D8, D12, G3, G12, H4, H13, J3, J12, M4, M7, M9, M13, N12	3, 24, 46, 92, 114, 160
VCCIO	–	–	–	–	16, 40, 60, 69, 91, 112, 122, 141	–	23, 47, 57, 69, 79, 104, 127, 137, 149, 159

Table 54. FLEX 8000 225-, 232-, 240-, 280- & 304-Pin Package Pin-Outs (Part 2 of 3)						
Pin Name	**225-Pin BGA EPF8820A**	**232-Pin PGA EPF81188A**	**240-Pin PQFP EPF81188A**	**240-Pin PQFP EPF81500A**	**280-Pin PGA EPF81500A**	**304-Pin RQFP EPF81500A**
DATA4	A5	C7	198	194	W16	248
DATA3	B5	D7	196	193	W17	246
DATA2	E6	B5	194	190	V16	243
DATA1	D5	A3	191	189	U16	241
DATA0	C4	A2	189	187	V17	239
SDOUT *(3)*	K1	N2	135	136	F19	169
TDI	F15 *(4)*	–	–	63 *(14)*	B1 *(14)*	80 *(14)*
TDO	J2 *(4)*	–	–	117	C17	149
TCK *(6)*	J14 *(4)*	–	–	116 *(14)*	A19 *(14)*	148 *(14)*
TMS	J12 *(4)*	–	–	64 *(14)*	C2 *(14)*	81 *(14)*
TRST *(7)*	P14	–	–	115 *(14)*	A18 *(14)*	145 *(14)*
Dedicated Inputs *(10)*	F4, L1, K12, E15	C1, C17, R1, R17	10, 51, 130, 171	8, 49, 131, 172	F1, F16, P3, P19	12, 64, 164, 217
VCCINT (5.0 V)	F5, F10, E1, L2, K4, M12, P15, H13, H14, B15, C13	E4, H4, L4, P12, L14, H14, E14, R14, U1	20, 42, 64, 66, 114, 128, 150, 172, 236	18, 40, 60, 62, 91, 114, 129, 151, 173, 209, 236	B17, D3, D15, E8, E10, E12, E14, R7, R9, R11, R13, R14, T14	24, 54, 77, 144, 79, 115, 162, 191, 218, 266, 301
VCCIO (5.0 V or 3.3 V)	H3, H2, P6, R6, P10, N10, R14, N13, H15, H12, D12, A14, B10, A10, B6, C6, A2, C3, M4, R2	N10, M13, M5, K13, K5, H13, H5, F5, E10, E8, N8, F13	19, 41, 65, 81, 99, 116, 140, 162, 186, 202, 220, 235	17, 39, 61, 78, 94, 108, 130, 152, 174, 191, 205, 221, 235	D14, E7, E9, E11, E13, R6, R8, R10, R12, T13, T15	22, 53, 78, 99, 119, 137, 163, 193, 220, 244, 262, 282, 300

Notes to tables:

(1) Perform a complete thermal analysis before committing a design to this device package. See *Application Note 74 (Evaluating Power for Altera Devices)* for more information.
(2) This pin is a dedicated pin and is not available as a user I/O pin.
(3) `SDOUT` will drive out during configuration. After configuration, it may be used as a user I/O pin. By default, the MAX+PLUS II software will not use `SDOUT` as a user I/O pin; the user can override the MAX+PLUS II software and use `SDOUT` as a user I/O pin.
(4) If the device is not configured to use the JTAG BST circuitry, this pin is available as a user I/O pin.
(5) JTAG pins are available for EPF8636A devices only. These pins are dedicated user I/O pins.
(6) If this pin is used as an input in user mode, ensure that it does not toggle before or during configuration.
(7) `TRST` is a dedicated input pin for JTAG use. This pin must be grounded if JTAG BST is not used.
(8) Pin 52 is a V_{CC} pin on EPF8452A devices only.
(9) The user I/O pin count includes dedicated input pins and all I/O pins.
(10) Unused dedicated inputs should be tied to ground on the board.
(11) `SDOUT` does not exist in the EPF8636GC192 device.
(12) These pins are no connect (N.C.) pins for EPF8636A devices only. They are user I/O pins in EPF8820A devices.
(13) EPF8636A devices have 132 user I/O pins; EPF8820A devices have 148 user I/O pins.
(14) For EPF81500A devices, these pins are dedicated JTAG pins and are not available as user I/O pins. If JTAG BST is not used, `TDI`, `TCK`, `TMS`, and `TRST` should be tied to `GND`.

Revision History

The information contained in the *FLEX 8000 Programmable Logic Device Family Data Sheet* version 11.1 supersedes information published in previous versions. The *FLEX 8000 Programmable Logic Device Family Data Sheet* version 11.1 contains the following change: minor textual updates.